

RF Exposure Report

Report No.: SA150504C40A

FCC ID: T5UAQT80

Test Model: AQT80

Received Date: May 04, 2015

Test Date: Aug. 24 ~ Aug. 27, 2015

Issued Date: Aug. 27, 2015

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Release Control Record

Issue No.	Description	Date Issued
SA150504C40A	Original release	Aug. 27, 2015

1 Certificate of Conformity

Product: LTE Tablet PC
Brand: Sprint
Test Model: AQT80
Sample Status: Engineering sample
Applicant: Quanta Microsystems, Inc.
Test Date: Aug. 24 ~ Aug. 27, 2015
Standards: FCC Part 2 (Section 2.1093)
KDB 447498 D03
IEEE C95.1

The above equipment has been tested by **Bureau Veritas Consumer Products Services (H.K.) Ltd., Taoyuan Branch**, and found compliance with the requirement of the above standards. The test record, data evaluation & Equipment Under Test (EUT) configurations represented herein are true and accurate accounts of the measurements of the sample's EMC characteristics under the conditions specified in this report.

Prepared by : Jvy Lin , **Date:** Aug. 27, 2015
Jvy Lin / Specialist

Approved by : Ken Liu , **Date:** Aug. 27, 2015
Ken Liu / Senior Manager

2 Evaluation Result

Following FCC KDB 447498 D01 “General SAR test exclusion guidance”

The corresponding SAR Exclusion Threshold condition, listed below:

- 1) The 1-g and 10-g SAR test exclusion thresholds for 100 MHz to 6 GHz at test separation distances ≤ 50 mm are determined by:
[(max. power of channel, including tune-up tolerance, mW)/(min. test separation distance, mm)] $\cdot [\sqrt{f(\text{GHz})}]$
 ≤ 3.0 for 1-g SAR and ≤ 7.5 for 10-g extremity SAR, where
 - f(GHz) is the RF channel transmit frequency in GHz.
 - Power and distance are rounded to the nearest mW and mm before calculation.
 - The result is rounded to one decimal place for comparison. The test exclusions are applicable only when the minimum test separation distance is ≤ 50 mm and for transmission frequencies between 100 MHz and 6 GHz. When the minimum test separation distance is < 5 mm, a distance of 5 mm is applied to determine SAR test exclusion.
- 2) At 100 MHz to 6 GHz and for test separation distances > 50 mm, the SAR test exclusion threshold is determined according to the following:
 - a) [Threshold at 50 mm in step 1) + (test separation distance - 50mm) \cdot (f(MHz)/150)] mW, at 100MHz to 1500 MHz
 - b) [Threshold at 50 mm in step 1) + (test separation distance - 50 mm) \cdot 10] mW at > 1500 MHz and ≤ 6 GHz
- 3) At frequencies below 100 MHz, the following may be considered for SAR test exclusion.
 - a) The threshold at the corresponding test separation distance at 100 MHz in step 2) is multiplied by $[1 + \log(100/f(\text{MHz}))]$ for test separation distances > 50 mm and < 200 mm.
 - b) The threshold determined by the equation in a) for 50 mm and 100 MHz is multiplied by $\frac{1}{2}$ for test separation distances ≤ 50 mm.
 - c) SAR measurement procedures are not established below 100 MHz. When SAR test exclusion cannot be applied, a KDB inquiry is required to determine SAR evaluation requirements for any test results to be acceptable.

3 SAR Test Exclusion Thresholds

Maximum measured transmitter power:

Frequency (GHz)	Max. Power (mW)	Min. test separation distance (mm)	SAR test exclusion calculation value ^(NOTE 2)	1-g SAR test exclusion thresholds	Result
BT LE	0.9141	5	0.283	3	Pass
BT EDR	3.112	5	0.964	3	Pass

NOTE: 1. The antenna type is FPC antenna with -0.3dBi gain.
2. Calculate SAR test exclusion thresholds from condition "1" formulas.

4 Conclusion

Since Source-base time average power is below SAR test exclusion power thresholds, the SAR evaluation is not required.

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